SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

- Bidirectional Transceiver
- Meets or Exceeds the Requirements of TIA/EIA-422-B, TIA/EIA-485-A, and ITU Recommendation V.11
- High-Speed Advanced Low-Power Schottky Circuitry
- Low Skew . . . 6 ns Max
- Designed for Multipoint Transmission on Long Bus Lines in Noisy Environments
- Low Supply-Current Requirements . . . 30 mA Max
- Wide Positive and Negative Input/Output Bus-Voltage Ranges
- Driver Output Capacity . . . ±60 mA
- Thermal-Shutdown Protection
- Driver Positive and Negative Current Limiting
- Receiver Input Impedances . . . 12 kΩ Min
- Receiver Input Sensitivity . . . ±200 mV Max
- Receiver Input Hysteresis . . . 120 mV Typ
- Fail Safe . . . High Receiver Output With Inputs Open
- Operates From a Single 5-V Supply
- Glitch-Free Power-Up and Power-Down Protection
- Interchangeable With National DS3695 and DS3695A

description

The TL3695 differential bus transceiver is designed for bidirectional data communication on multipoint bus-transmission lines. It is designed for balanced transmission lines and meets TIA/EIA-422-B, TIA/EIA-485-A, and ITU Recommendation V.11.

The TL3695 combines a 3-state differential line driver and a differential input line receiver, both of which operate from a single 5-V power supply. The driver and receiver have active-high and active-low enables, respectively, which can be externally connected together to function as a directional control. The driver differential outputs and the receiver differential inputs are connected internally to form a differential input/output (I/O) bus port that is designed to offer minimum loading to the bus when the driver is disabled or $V_{CC} = 0$. This port features wide positive and negative common-mode voltage ranges, making the device suitable for party line applications.

The TL3695 is characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



D OR P PACKAGE (TOP VIEW)								
R	1	υ	8] V _{CC}				
RE	2		7] B				
DE	3		6] A				
D	4		5] GND				

SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

AVAILABLE OPTIONS

	PACKAGED DEVICES				
т _А	SMALL OUTLINE	PLASTIC DIP			
	(D)	(P)			
0°C to 70°C	TL3695D	TL3695P			

The D package is available taped and reeled. Add the suffix R to device type (e.g., TL3695DR).

Function Tables

DRIVER

INPUT	ENABLE	Ουτι	PUTS
D	DE	Α	В
Н	Н	Н	L
L	Н	L	Н
х	L	Z	Z

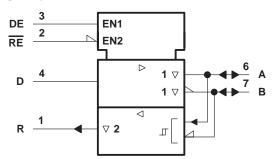
H = high level, L = low level, ? = indeterminate,

X = irrelevant, Z = high impedance (off)

DIFFERENTIAL INPUTS A – B	ENABLE RE	OUTPUT R
$V_{ID} \ge 0.2 V$	L	Н
$-0.2 \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$	L	?
$V_{ID} \leq -0.2 V$	L	L
Х	Н	Z
Inputs open	L	н

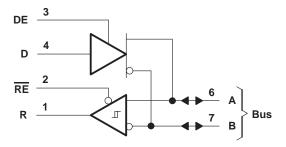
H = high level, L = low level, ? = indeterminate, X = irrelevant, Z = high impedance (off)

logic symbol[†]



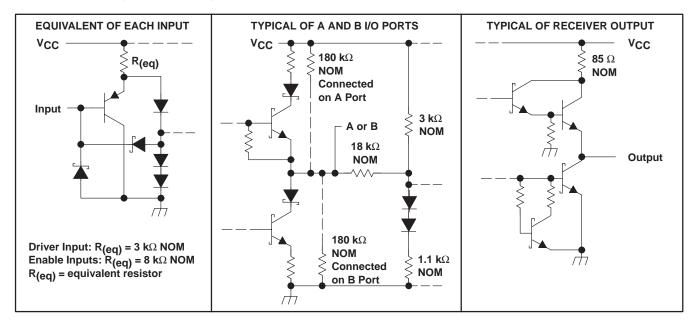
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999



schematic of inputs and outputs

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} (see Note 1)	
Voltage range at any bus terminal	
Enable input voltage, V _I	5.5 V
Operating free-air temperature range, T _A	0°C to 70°C
Package thermal impedance, θ_{JA} (see Note 2): D package	97°C/W
PW package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T _{stg}	–65°C to 150°C

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential I/O bus voltage, are with respect to network ground terminal.

2. The package thermal impedance is calculated in accordance with JESD 51.



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}			5	5.25	V
oltage at any bus terminal (separately or common mode), VI or VIC				12	V
				-7	v
High-level Input voltage, VIH	D, DE, and RE	2			V
Low-level Input voltage, VIL	D, DE, and RE			0.8	V
Differential input voltage, VID (see Note 3)				±12	V
High lovel output outroot love	Driver			- 60	mA
High-level output current, IOH	Receiver			- 400	μΑ
	Driver			60	~^^
Low-level output current, IOL	Receiver			8	mA
Operating free-air temperature, TA		0		70	°C

NOTE 3: Differential input/output bus voltage is measured at the noninverting terminal A with respect to the inverting terminal B.



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]		MIN	TYP‡	MAX	UNIT
VIK	Input clamp voltage	II = -18 mA				-1.5	V
VO	Output voltage	I _O = 0		0		6	V
VOD1	Differential output voltage	I _O = 0		1.5		5	V
VOD2	Differential output voltage	R _L = 100 Ω,	See Figure 1	1/2 V _{OD1} or 2§			V
		R _L = 54 Ω,	See Figure 1	1.5	2.5	5	V
V _{OD3}	Differential output voltage	$V_{\text{test}} = -7 \text{ V to } 12 \text{ V},$	See Figure 2	1.5		5	V
$\Delta V_{OD} $	Change in magnitude of differential output voltage¶					±0.2	V
Voc	Common-mode output voltage	R _L = 54 Ω,	See Figure 1			3	V
$\Delta V_{OC} $	Change in magnitude of common-mode output voltage¶					±0.2	V
1-		Output disabled,	V _O = 12 V			1	A
10	Output current	See Note 4	$V_{O} = -7 V$			-0.8	mA
Iн	High-level input current	V _I = 2.4 V				20	μΑ
۱ _{IL}	Low-level input current	V _I = 0.4 V				-200	μΑ
		VO = -6 V				-250	
IOS	Short-circuit output current#	$V_{O} = 0$				-150	mA
		$V_{O} = V_{CC}$				250	ША
		V _O = 8 V				250	
	Supply current	No load	Outputs enabled		23	50	mA
ICC	Supply current	Ino luau	Outputs disabled		19	35	III/A

[†] The power-off measurement in TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs.

[‡] All typical values are at $V_{CC} = 5$ V and $T_A = 25^{\circ}$ C.

§ The minimum V_{OD2} with a 100-Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

 $\Delta |V_{OC}|$ and $\Delta |V_{OC}|$ are the changes in magnitude of V_{OD} and V_{OC} , respectively, that occur when the input is changed from a high level to a low level.

[#] Duration of the short circuit should not exceed one second for this test.

NOTE 4: This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature

PARAMETER		TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
td(OD)	Differential-output delay time					8	22	ns
	Skew (t _{d(ODH)} – t _{d(ODL)})	$C_{L1} = C_{L2} = 100 \text{ pF},$	$R_L = 60 \Omega$,	See Figure 3		1	8	ns
t _{t(OD)}	Differential output transition time					8	18	ns
^t PZH	Output enable time to high level	C _L = 100 pF,	R _L = 500 Ω,	See Figure 4			50	ns
^t PZL	Output enable time to low level	C _L = 100 pF,	RL = 500 Ω,	See Figure 5			50	ns
^t PHZ	Output disable time from high level	CL = 15 pF,	RL = 500 Ω,	See Figure 4		8	30	ns
^t PLZ	Output disable time from low level	C _L = 15 pF,	R _L = 500 Ω,	See Figure 5		8	30	ns

[‡] All typical values are at $V_{CC} = 5$ V and $T_A = 25^{\circ}C$.



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

	SYMBOL EQUIVALENTS						
DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A					
Vo	V _{oa} , V _{ob}	V _{oa} , V _{ob}					
IVOD1	Vo	Vo					
IVOD2	V _t (R _L = 100 Ω)	V _t (R _L = 54 Ω)					
IV0D3I		V _t (test termination measurement 2)					
V _{test}		V _{tst}					
$\Delta V_{OD} $	$ V_t - \overline{V}_t $	$ V_t - \overline{V}_t $					
Voc	V _{os}	V _{os}					
	V _{OS} – V _{OS}	$ V_{OS} - \overline{V}_{OS} $					
IOS	I _{sa} , I _{sb}						
IO	I _{xa} , I _{xb}	l _{ia} , l _{ib}					

RECEIVER SECTION

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST C	ONDITIONS	MIN	түр†	MAX	UNIT
VIT+	Positive-going input threshold voltage	V _O = 2.7 V,	$I_{O} = -0.4 \text{ mA}$			0.2	V
V _{IT} _	Negative-going input threshold voltage	V _O = 0.5 V,	IO = 8 mA	-0.2‡			V
V _{hys}	Hysteresis voltage (V _{IT+} –V _{IT–})	$V_{OC} = 0$			70		mV
VIK	Enable-input clamp voltage	l _l = –18 mA				-1.5	V
VOH	High-level output voltage	$V_{ID} = 200 \text{ mV or in}$ $I_{OH} = -400 \mu\text{A},$	$V_{ID} = 200 \text{ mV}$ or inputs open, $I_{OH} = -400 \mu A$, See Figure 6				V
M.		$V_{ID} = -200 \text{ mV},$	I _{OL} = 16 mA			0.5	V
VOL	Low-level output voltage	See Figure 6	IOL = 8 mA			0.45	
IOZ	High-impedance-state output current	V _O = 0.4 V to 2.4 V	/			±20	μA
1.		Other input = 0,	VI = 12 V			1	~
1	Line input current	See Note 5	$V_{I} = -7 V$		2	-0.8	mA
IIН	High-level enable-input current	V _{IH} = 2.7 V	-			20	μA
١ _{IL}	Low-level enable-input current	V _{IL} = 0.4 V				-100	μA
rj	Input resistance			12			kΩ
los	Short-circuit output current§	V _O = 0		-15		-85	mA
1		Nalaad	Outputs enabled		23	50	~
ICC	Supply current	No load	Outputs disabled		19	35	mA

[†] All typical values are at V_{CC} = 5 V and T_A = 25°C. [‡] The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage and threshold voltage levels only.

§ Duration of the short circuit should not exceed one second for this test.

NOTE 5: This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions.



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

switching characteristics over recommended ranges of supply voltage and operating free-air temperature range, $C_L = 15 \text{ pF}$

	PARAMETER	TEST CONDITIONS	MIN	түр†	MAX	UNIT
tPLH	Propagation delay time, low- to high-level output	$V_{ID} = -1.5 V$ to 1.5 V, See Figure 7		14	37	ns
t _{PHL}	Propagation delay time, high- to low-level output			14	37	ns
^t PZH	Output enable time to high level	See Figure 8		7	20	ns
t _{PZL}	Output enable time to low level			7	20	ns
^t PHZ	Output disable time from high level	See Figure 8		7	16	ns
t _{PLZ}	Output disable time from low level			8	16	ns

[†] All typical values are at $V_{CC} = 5$ V and $T_A = 25^{\circ}C$.

PARAMETER MEASUREMENT INFORMATION

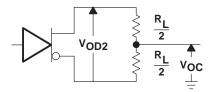
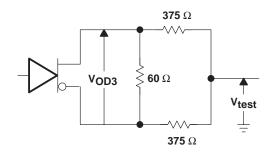
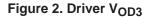
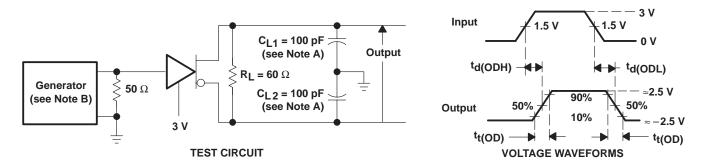


Figure 1. Driver V_{OD} and V_{OC}







NOTES: A. CL includes probe and jig capacitance.

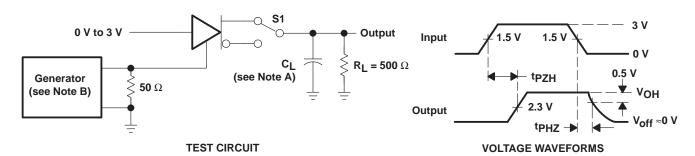
B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 6 ns, t_f \leq 6 ns, Z_Q = 50 Ω .





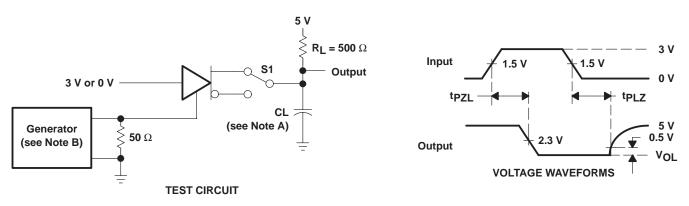
SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. CL includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 10 ns, t_f \leq 10 ns, Z_O = 50 Ω .





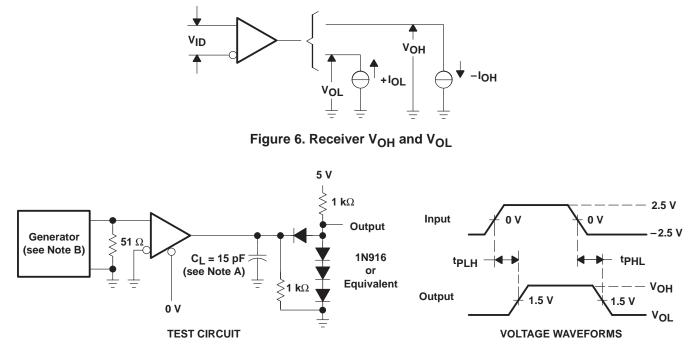
- NOTES: A. CL includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 10 ns, t_f \leq 10 ns, Z_Q = 50 Ω .

Figure 5. Driver Test Circuit and Voltage Waveforms



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

PARAMETER MEASUREMENT INFORMATION



NOTES: A. CL includes probe and jig capacitance.

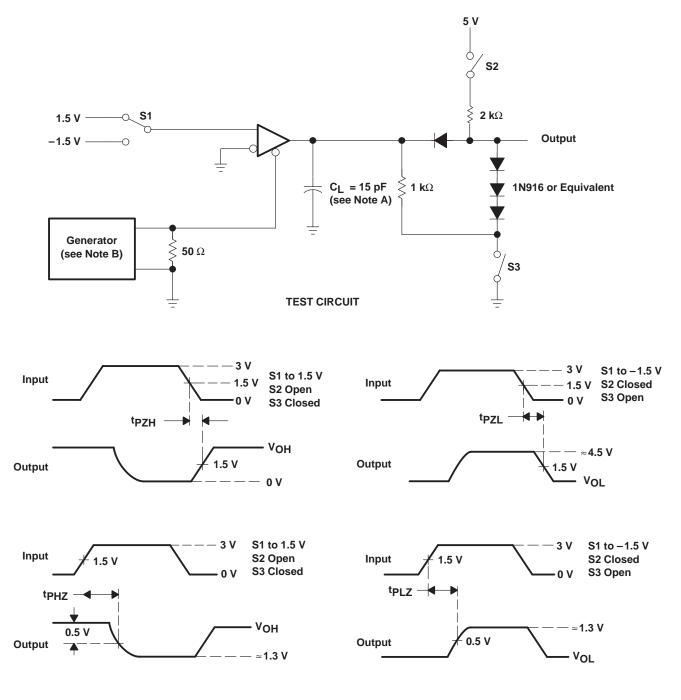
B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 10 ns, t_f \leq 10 ns, Z_O = 50 Ω .

Figure 7. Receiver Test Circuit and Voltage Waveforms



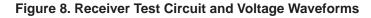
SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999





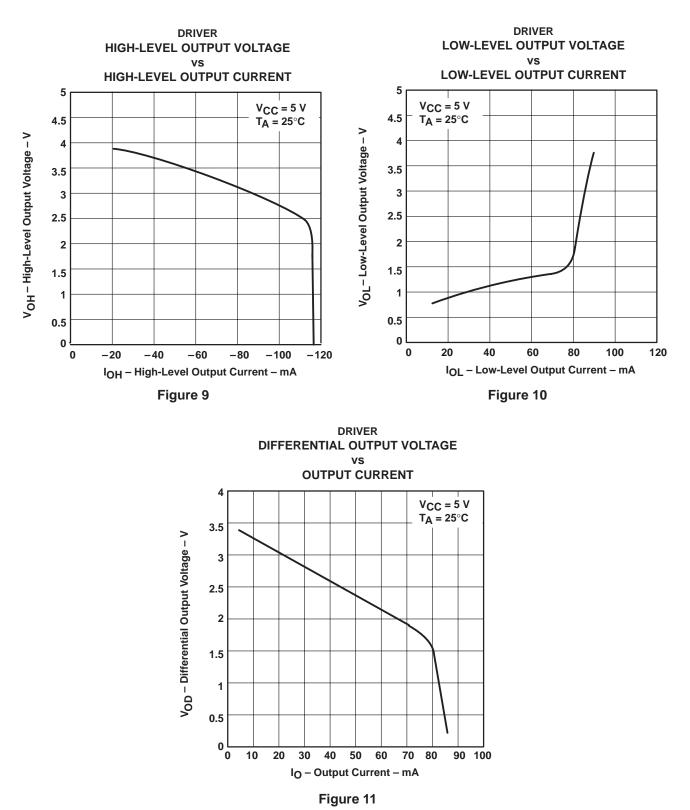
VOLTAGE WAVEFORMS

- NOTES: A. CL includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 10 ns, t_f \leq 10 ns, Z_O = 50 Ω .





SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

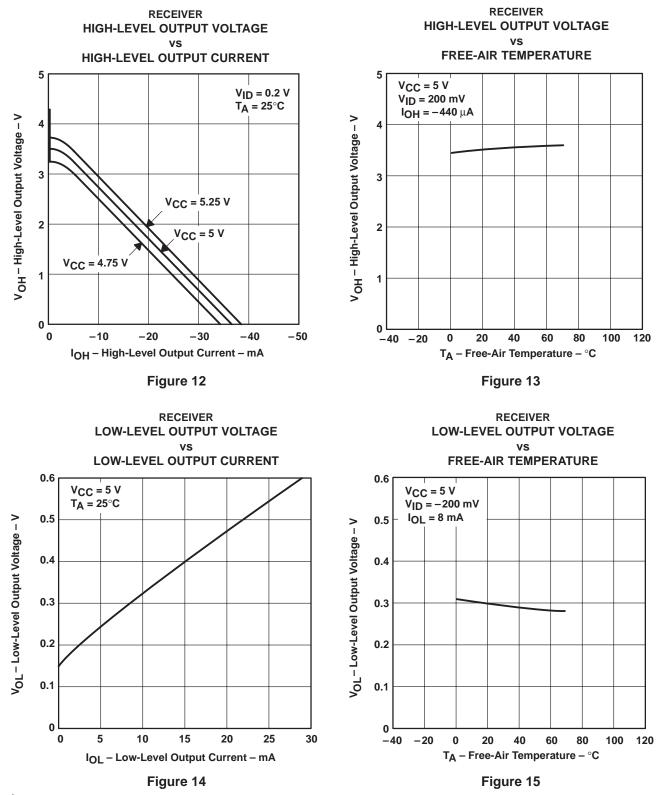


TYPICAL CHARACTERISTICS[†]

[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.



SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999

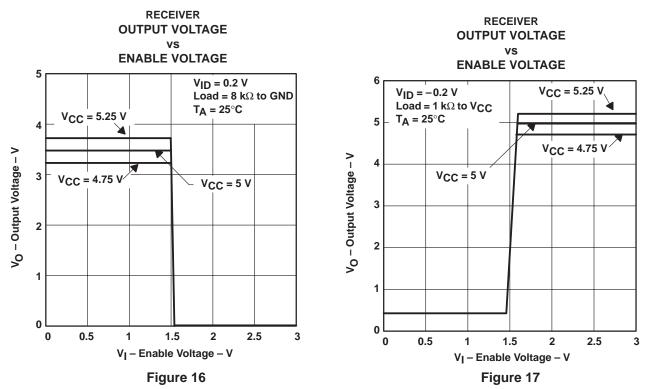


TYPICAL CHARACTERISTICS[†]

[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.



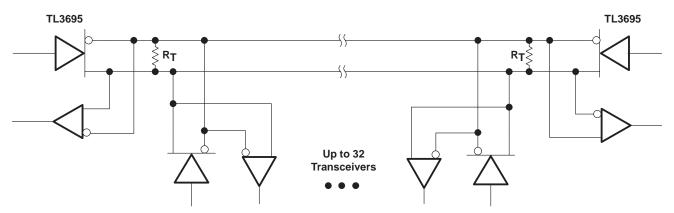
SLLS044D - NOVEMBER 1988 - REVISED DECEMBER 1999



TYPICAL CHARACTERISTICS[†]

[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

APPLICATION INFORMATION



NOTE A: The line should be terminated at both ends in its characteristic impedance (R_T = Z_O). Stub lengths off the main line should be kept as short as possible.

Figure 18. Typical Application Circuit



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